



**MS AF
RESPONSE UNDER 37 CFR 1.116
EXPEDITED PROCEDURE
EXAMINING GROUP 2829**

**PATENT
0763-0174P**

IN THE U.S. PATENT AND TRADEMARK OFFICE

*Entry approved.
E. H.
3-31-04*

APPLICANT:	Ha Zoong KIM	CONF.:	1610
APPL. NO.:	09/995,680	GROUP:	2829
FILED:	November 29, 2001	EXAMINER:	Karlsen, E.
FOR:	TDDB TEST PATTERN AND METHOD FOR TESTING TDDB OF MOS CAPACITOR DIELECTRIC		

RESPONSE UNDER 37 C.F.R. 1.116

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

March 23, 2004

Sir:

In response to the Examiner's Office Action dated December 23, 2003, the following amendments and remarks are respectfully submitted in connection with the above-identified application. The present Amendment includes changes to the claims and remarks.